protoDUNE-SP Cold Electronics Calibration

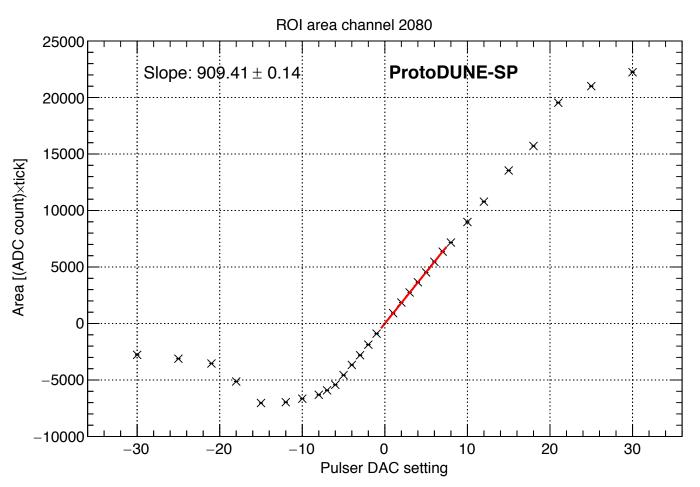
- Two in situ DAC available on the FEMB
 - "external" generated by the FPGA
 - "internal" generated by the FE ASIC
- Configure:
 - FPGA controls clock to generate all pulses:
 - Set FPGA to pulser mode, delay (relative to sampling clock), frequency
 - Decide between INT or EXT on each ASIC
 - Connect test capacitor to each FE channel input (channelwise)
 - Leaves channel input active
- Data-taking: each DAC setting is a unique run
 - All WIBs and FEMBs reconfigured
 - ~5 minutes to configure DAQ
 - 2 minutes/run
 - ~50 events each containing ~12 bipolar pulses

Analysis

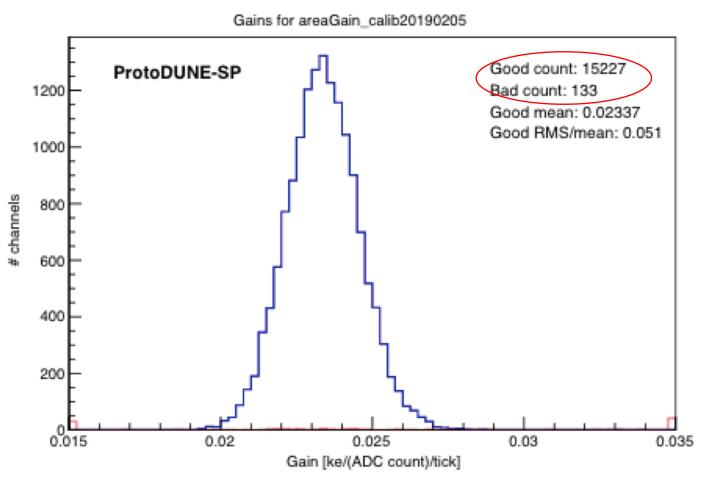
- Area of interest for calibration:
 - DAC 1-7
- At each DAC setting:
 - Average area under the pulse is plotted as a function of DAC value
 - Known DAC step size:

 $Q_s = 3.43 \text{ fC} = 21.4 \text{ k}e^{-1}$

• From fit and DAC size extract gain in e-/ADC



Gain and Issues



- Every channel was included in every DAC value run
 - Only several times did we take DAC values well into saturation
 - After that only DAC values 1-10 for the default detector gain and shaping time (14 mV/fC, 2 usec) were taken
- Slow and lots of deadtime!
- Solution (*not implemented*):
 - Use EXT pulser, 1 DAQ run
 - Configure all FEMBs 1 time
 - During run, raise the trigger inhibit every 5 minutes, change the DAC setting in the FPGA, lower inhibit, continue taking data